



IAP3 Rec'd PCT/PTO 23 DEC 2005

PCT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **Kenji WATANABE et al.**

Group Art Unit:

Serial Number: 10/543,151

Examiner:

Filed: July 25, 2005

Confirmation Number:

For: **MAPPING-PROJECTION-TYPE ELECTRON BEAM APPARATUS FOR
INSPECTING SAMPLE BY USING ELECTRONS EMITTED FROM THE
SAMPLE**

Attorney Docket Number: 052886
Customer Number: 38834

INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. §1.97(b)

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

December 23, 2005

Sir:

In compliance with 37 C.F.R. §1.56, Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08. This paper is being filed within the time periods set forth in 37 C.F.R. §1.97(b). A copy of each non-U.S. document is enclosed herewith.

The inventor considers Japanese Laid-open No. Hei 4-242060 to disclose a reflection election microscope having a similar electron beam deflection device.

If there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,
WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP


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SGA/arf
Enclosures: PTO/SB/08
3 Documents

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /K.N./

Complete if Known

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Application Number	10/543,151
Confirmation Number	
Filing Date	July 25, 2005 04-18-2006
First Named Inventor	Kenji WATANABE et al.
Art Unit	2881
Examiner Name	K. Nguyen
Attorney Docket Number	052886

Sheet 1 of 1

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
	1	US 5,576,833		11/19/1996	Miyoshi et al.
		US			
		US			
		US			
		US			
		US			
		US			
		US			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁴
		Country Code ³	Number ⁴	Kind Code ² (if known)			
	2	JP	4-242060		08/28/1992		

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁴
	3	K. Tsuno, "Simulation of a Wien filter as beam separator in a low energy electron microscope", pp. 127-140, Ultramicroscopy 55 (1994).	

Examiner Signature	/Kiet Tuan Nguyen/	Date Considered	08/17/2008
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /K.N./